Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	•
09/619,917	NOMURA ET AL.	
Examiner	Art Unit	-
Nhan T. Tran	2622	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED						
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated EAST search using previouly cited references	2/19/2007	NT		